

## -30V P-Channel Enhancement Mode MOSFET

### Description

The AP6P03SI uses advanced Trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = -30V$   $I_D = -6A$

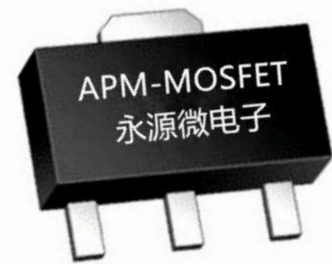
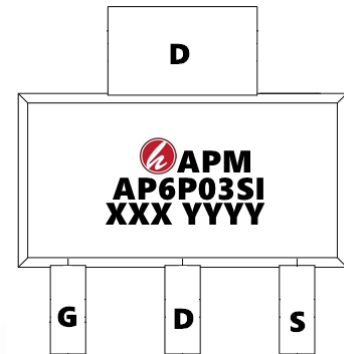
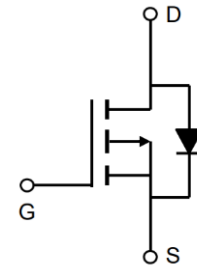
$R_{DS(ON)} < 55m\Omega$  @  $V_{GS}=10V$  (Type: 40m $\Omega$ )

### Application

Battery protection

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP6P03SI	SOT89-3L	AP6P03SI XXX YYYY	3000

### Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Max.	Units
VDSS	Drain-Source Voltage	-30	V
VGSS	Gate-Source Voltage	$\pm 20$	V
$I_D@T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-6.0	A
$I_D@T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-3.3	A
IDM	Pulsed Drain Current <sup>note1</sup>	-20.4	A
$P_D$	Power Dissipation $T_A = 25^\circ C$	2.15	W
R $\theta$ JA	Thermal Resistance, Junction to Ambient	70	$^\circ C/W$
TJ, TSTG	Operating and Storage Temperature Range	-55 to +150	$^\circ C$



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### Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

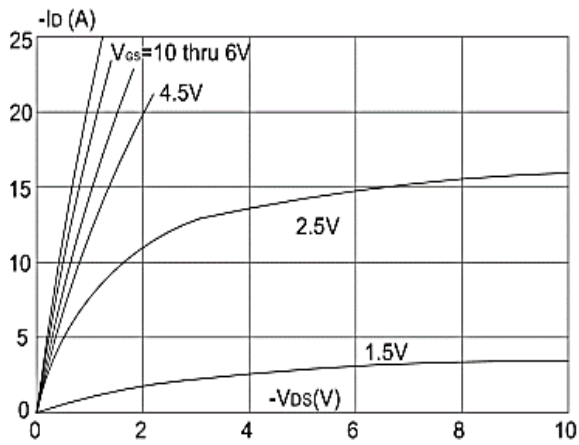
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> = -250μA	-30	-33	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -30V, V <sub>GS</sub> = 0V,	-	-	-1	μA
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-1.0	-1.6	-2.5	V
RDS(on)	Static Drain-Source on-Resistance note2	V <sub>GS</sub> = -10V, I <sub>D</sub> = -5A	-	40	55	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -4A	-	65	90	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -15V, V <sub>GS</sub> = 0V, f = 1.0MHz	-	596	-	pF
C <sub>oss</sub>	Output Capacitance		-	95	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	68	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -15V, I <sub>D</sub> = -5.1A, V <sub>GS</sub> = -10V	-	6.8	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	1	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	1.4	-	nC
td(on)	Turn-on Delay Time	V <sub>DD</sub> = -15V, I <sub>D</sub> = -1A, V <sub>GS</sub> = -10V, R <sub>GEN</sub> = 2.5Ω	-	14	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	61	-	ns
td(off)	Turn-off Delay Time		-	19	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	10	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	-5.1	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-20.4	A
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = -5.1A	-	-0.8	-1.2	V

Note :

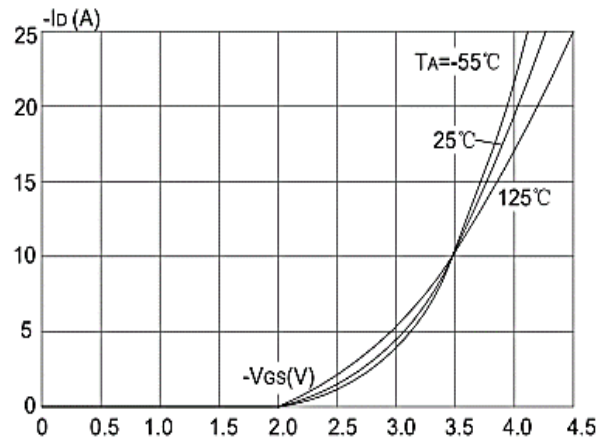
- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%
- 3、 The power dissipation is limited by 150°C junction temperature
- 4、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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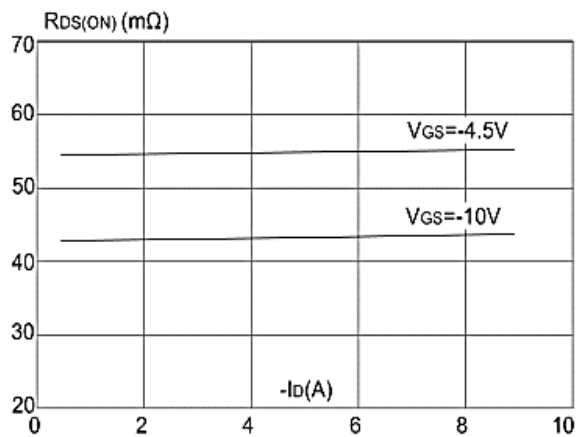
**Typical Characteristics**



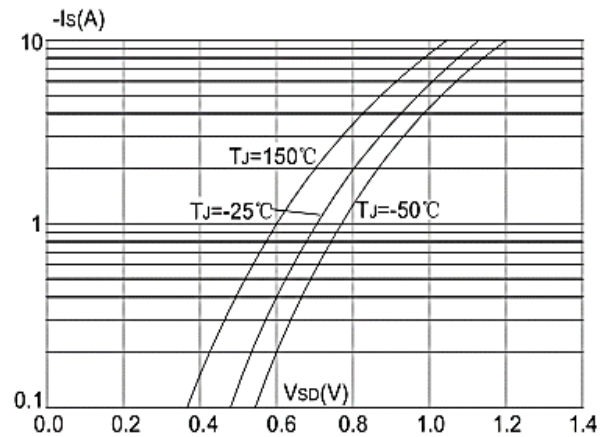
**Figure 1: Output Characteristics**



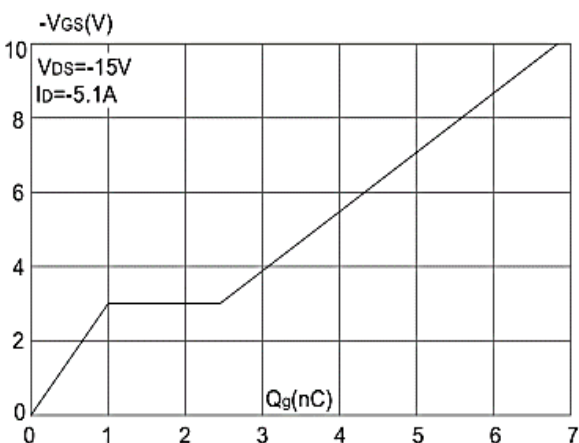
**Figure 2: Typical Transfer Characteristics**



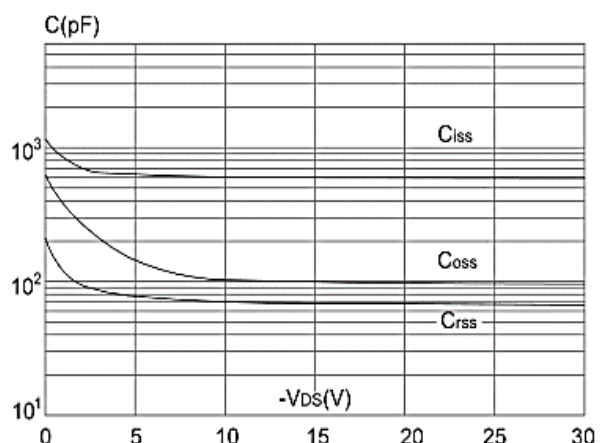
**Figure 3: On-resistance vs. Drain Current**



**Figure 4: Body Diode Characteristics**

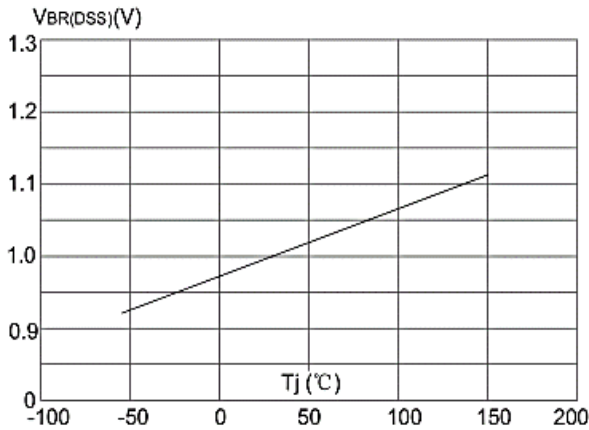


**Figure 5: Gate Charge Characteristics**

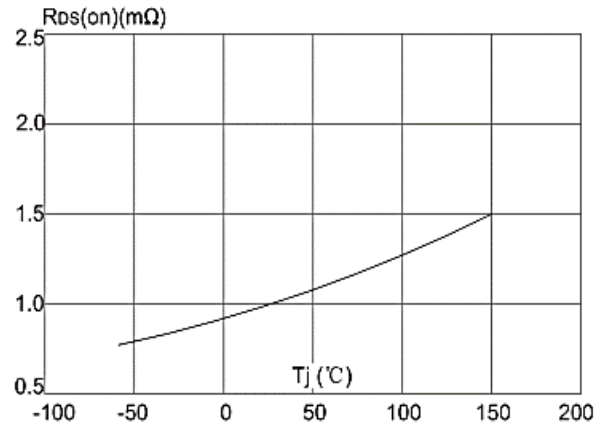


**Figure 6: Capacitance Characteristics**

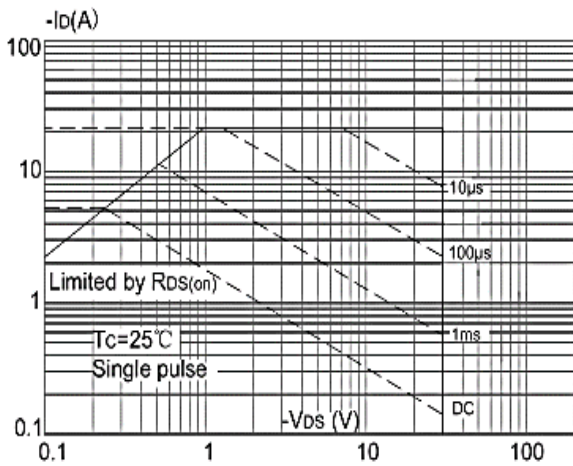
**-30V P-Channel Enhancement Mode MOSFET**



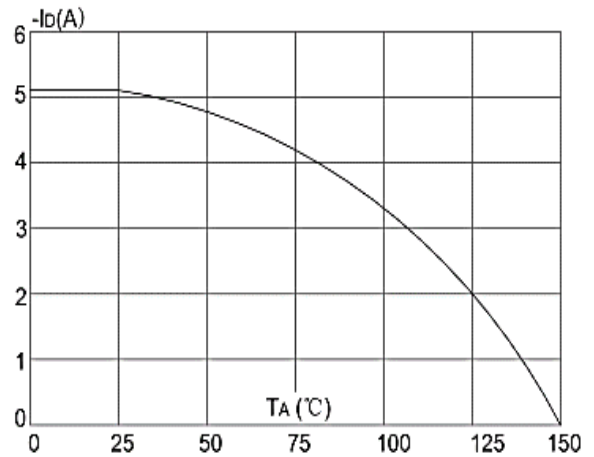
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



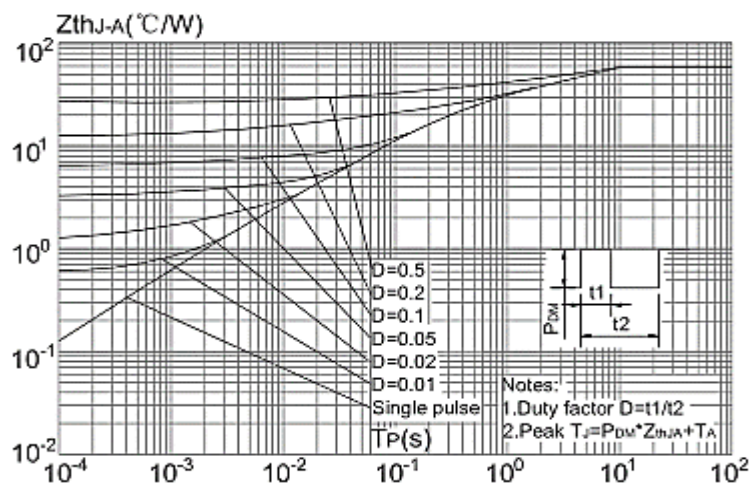
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area vs. Case Temperature**

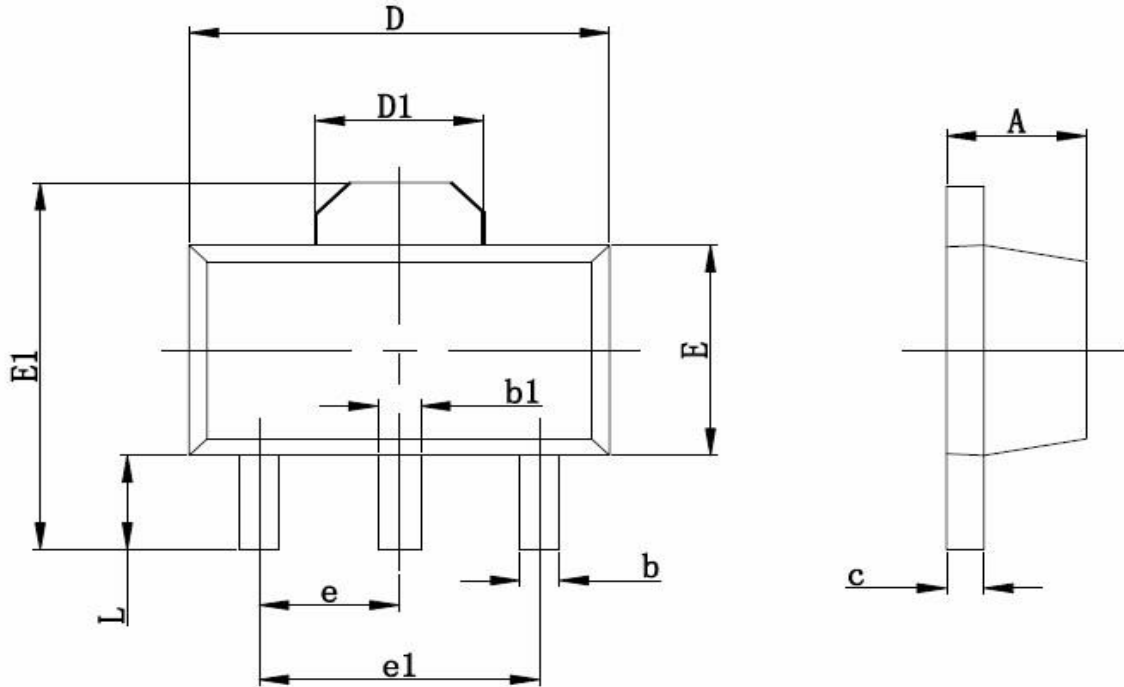


**Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature**



**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case**

**Package Mechanical Data:SOT89-3L**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.400	1.600	0.055	0.063
b	0.350	0.520	0.013	0.197
b1	0.400	0.580	0.016	0.023
c	0.350	0.440	0.014	0.017
D	4.400	4.600	0.173	0.181
D1	1.550 REF		0.061 REF	
E	2.350	2.550	0.091	0.102
E1	3.940	4.250	0.155	0.167
e	1.500 TYP		0.060TYP	
e1	3.000 TYP		0.118TYP	
L	0.900	1.100	0.035	0.047

**-30V P-Channel Enhancement Mode MOSFET****Attention**

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Edition	Date	Change
Rve1.0	2018/11/31	Initial release

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